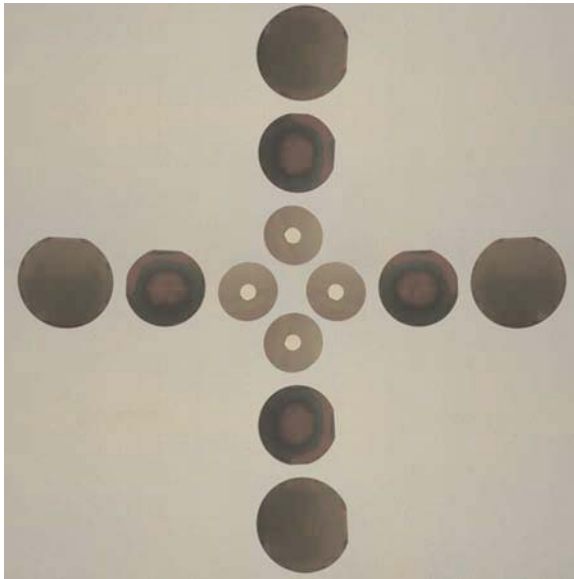




## Navigation on Hard Disk, Unpatterned Wafers and IC's



When working with scanning electron microscopes, atomic force microscopes and focused ion beams, one of the greatest time-consuming factors is locating very small features on large areas.

It has been estimated that up to 90% of equipment time logged is attributed to searching the sample to find the area of interest.

The problem becomes acute when the large areas contain complex patterns and small features such as those found on IC's, or contain no features at all, such as hard disk.